

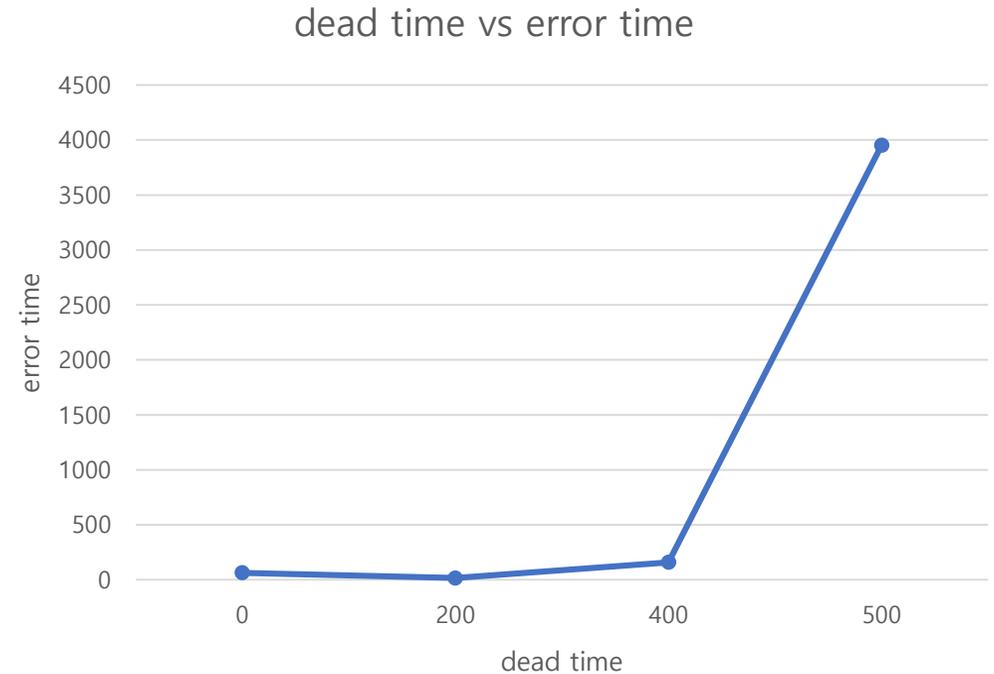
# Weekly report

SNU

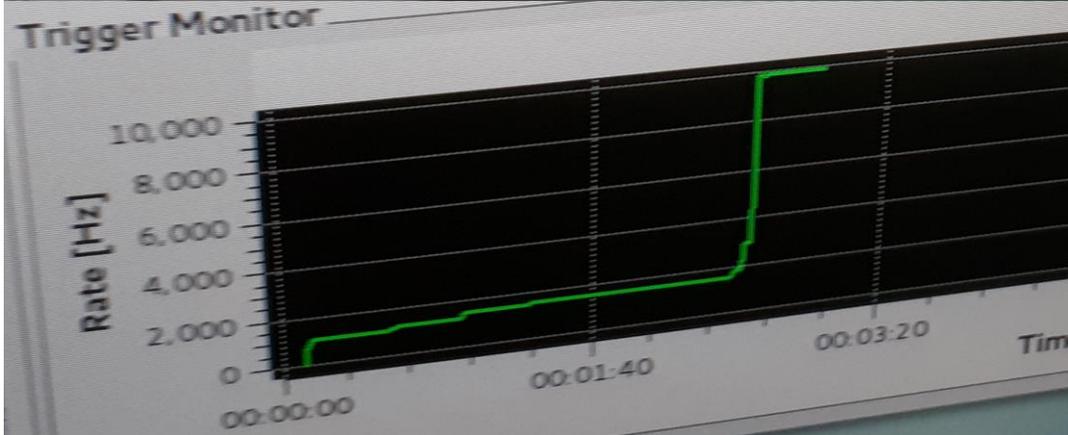
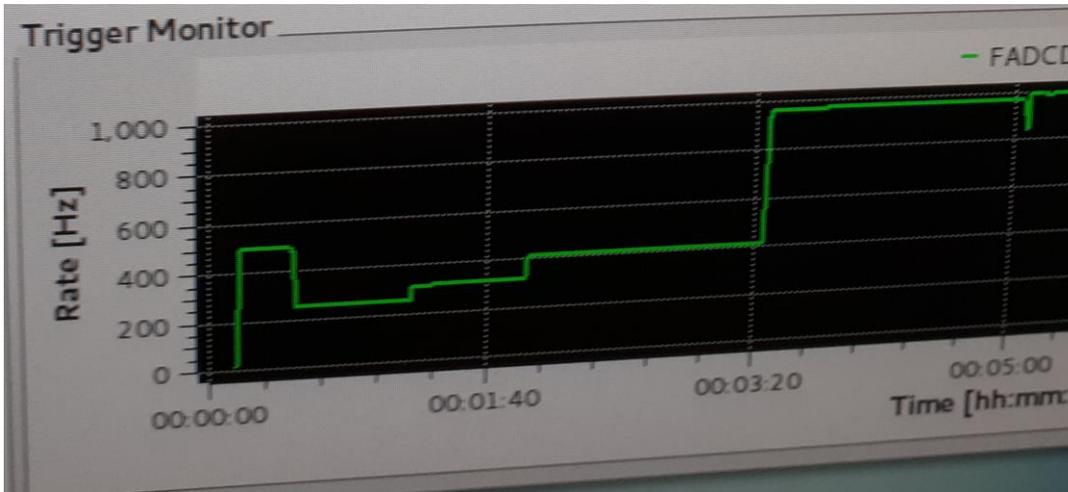
BongHo Kim

# TOF test (2 multiplicity)

- Error test with different dead time
- For 1 $\mu$ s record length, setup with 1 $\mu$ s dead time is tested for 3hour without error.
- For 500ns dead time, there was error after 1hour (1<sup>st</sup> trial) and no error for 1.5 hour (2<sup>nd</sup> trial)
- For 500ns record time, no error is shown for 300ns dead time.



# TOF test with pulse generator



- Data taking is tested with pulse generator (no HV, 1ch with pulse generator).
- Data taking tested with signal up to 10kHz. (no error)

→ Error may be happen by several trigger in one recording length.

Usual error messege shows "different trigger number and trigger time"

# Test with different parameters.

- PCI (pulse count interval) values from 10 to  $1.0e9$  were tested but there was no difference..
- Delay time also give no effect for error.
- Do we really need 1us window?
- Do we need 200ns coincidence width?

# Question about anti-p trap from others

- What is expected beam length, emittance and energy spread?
- What is expected schedule about anti-p trap?  
← End of 2018 or beginning of 2019 ?